

Notice of References Cited

Application/Control No.

10/047,280

Applicant(s)/Patent Under
Re xamination
YIP ET AL.

Examiner

Tanh Q. Nguyen

Art Unit

2182

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U.S. PATENT DOCUMENTS

* * *		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0169521 A1	11-2002	Goodman et al.	700/245
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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